Single Cell Li-Ion Battery Fuel Gauge for Battery Pack Integration

Check for Samples: **bq27411-G1**

FEATURES

- **Single Series Cell Li-Ion Battery Fuel Gauge**
  - **Resides in Battery Pack**
  - **Low-Value external Sense Resistor (10mΩ typical)**
  - **One Time Programmable (OTP) configuration Non-Volatile Memory (NVM)**
  - **Powered directly from battery with integrated LDO**
  - **400-kHz I²C serial interface**
  - **Internal temperature sensor, or Host reported temperature**
- **Easy to configure fuel gauging based on patented Impedance Track™ technology**
  - **Reports Remaining Capacity and State of Charge (SOC) with Smoothing Filter**
  - **Automatically adjusts for battery aging, self-discharge, temperature, and rate changes**
  - **Battery State of Health (aging) estimation**
- **Small 12-pin 2.5 mm × 4 mm SON Package**

APPLICATIONS

- **Smartphones, Feature phones and Tablets**
- **Digital Still and Video Cameras**
- **Handheld Terminals**
- **MP3 or Multimedia Players**

DESCRIPTION

The Texas Instruments bq27411-G1 is an easy to configure fuel gauging solution for single series cell Li-Ion battery packs. The device requires minimal configuration and uses One Time Programmable (OTP) Non-Volatile Memory (NVM) to avoid an initialization download by the system processor.

The bq27411-G1 uses the patented Impedance Track™ algorithm for fuel gauging, and provides information such as remaining battery capacity (mAh), state-of-charge (%), and battery voltage (mV).

The small 12-pin 2.5 mm × 4 mm SON package is ideal for space constrained applications.

TYPICAL APPLICATION
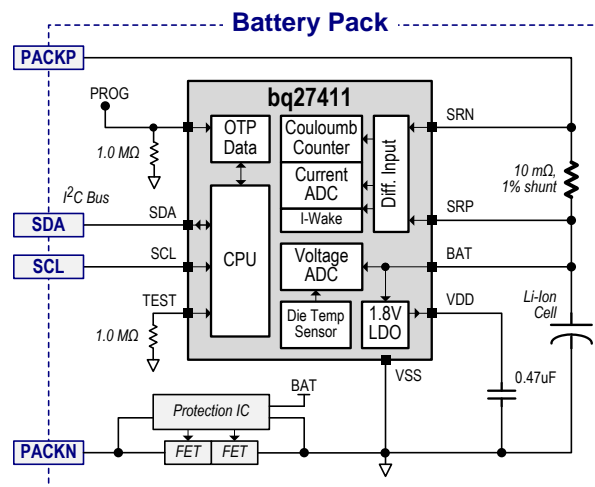
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.
Impedance Track is a trademark of Texas Instruments.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DEVICE INFORMATION

AVAILABLE OPTIONS

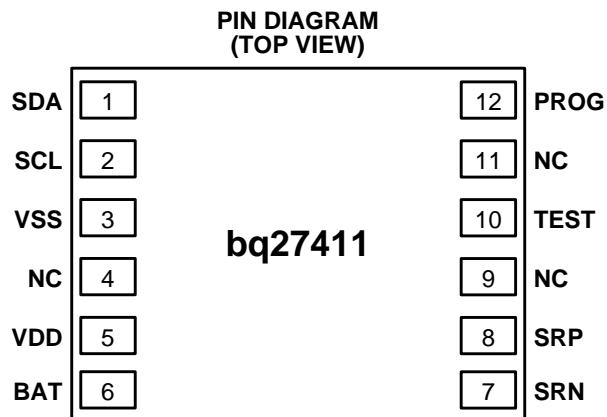| PART NUMBER	BATTERY TYPE	CHEM_ID [1]	DM_CODE [2]	FIRMWARE VERSION [3]	PACKAGE [4]	T_A	TAPE and REEL QUANTITY
bq27411DRZR-G1A	LiCoO$_2$ (4.2 V max charge)	0x0128	0x80	1.09 (0x0109)	12-pin, 2.5 × 4 mm SON	–40°C to 85°C	3000
bq27411DRZT-G1A							250
bq27411DRZR-G1B	LiMn$_2$O$_4$ (4.3 V max charge)	0x0312	0x90				3000
bq27411DRZT-G1B							250
bq27411DRZR-G1C	LiMn$_2$O$_4$ (4.35 V max charge)	0x0354	0xA0				3000
bq27411DRZT-G1C							250

(1) Refer to the CHEM_ID subcommand to confirm the battery chemistry type.
(2) Refer to the DM_CODE subcommand to confirm the Data Memory code.
(3) Refer to the FW_VERSION subcommand to confirm the firmware version.
(4) For the most current package and ordering information see the Package Option Addendum at the end of this document; or, see the TI website at www.ti.com.

THERMAL INFORMATION

THERMAL METRIC[1]		bq27411-G1 DRZ (12-PINS)	UNITS
θ_{JA}	Junction-to-ambient thermal resistance	64.1	°C/W
θ_{JCtop}	Junction-to-case (top) thermal resistance	59.8	
θ_{JB}	Junction-to-board thermal resistance	52.7	
ψ_{JT}	Junction-to-top characterization parameter	0.3	
ψ_{JB}	Junction-to-board characterization parameter	28.3	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance	2.4	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.

Product Folder Links: *bq27411-G1*

PIN DIAGRAM AND PACKAGE DIMENSIONS

**PIN DIAGRAM
(TOP VIEW)**

SDA	1	12	PROG
SCL	2	11	NC
VSS	3	10	TEST
NC	4	9	NC
VDD	5	8	SRP
BAT	6	7	SRN

bq27411

12-pin VSON, 2.5 x 4mmm 0.4mm pitch

PIN FUNCTIONS

PIN NAME	NO.	TYPE[1]	DESCRIPTION
BAT	6	PI, AI	LDO regulator input, battery voltage input, and coulomb counter input typically connected to the PACK+ terminal.
VDD	5	PO	1.8V Regulator Output. Decouple with 0.47µF ceramic capacitor to Vss. This pin is not intended to provide power for other devices in the system.
VSS	3	PI	Ground pin.
SRP	8	AI	Coulomb counter differential inputs expecting an external 10mΩ, 1% sense resistor. Connect SRP to BAT (CELLP)
SRN	7	AI	and connect SRN to PACKP. Refer to application diagram.
PROG	12	DO	Programming voltage input for the One Time Programmable (OTP) memory to be used during customer factory configuration. To avoid a floating input condition, recommend terminating with a 1.0MΩ (typical) pull-down resistor to VSS for reduced power consumption.
SDA	1	DIO	Slave I^{2}C serial bus for communication with system (Master). Open-drain pins. Use with external 5 - 10kΩ pull-up
SCL	2	DIO	resistors (typical) for each pin. If the external pull-up resistors will be disconnected from these pins during normal operation, recommend using external 1.0MΩ pull-down resistors to VSS at each pin to avoid floating inputs.
TEST	10	DI	This digital factory TEST pin must be pulled low for proper operation in customer's application. Recommend terminating with a 1.0MΩ (typical) pull-down resistor to VSS for reduced power consumption.
NC	4, 8, 11	--	No internal connection. May be left floating or tied to VSS.

(1) I/O = Digital input/output, IA = Analog input, P = Power connection

ELECTRICAL SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)[1]

	PARAMETER	MIN	MAX	UNIT
V_{BAT}	BAT pin input voltage range	−0.3	6	V
V_{SR}	SRP and SRN pins input voltage range	-0.3	$[V_{BAT} + 0.3]$	V
	Differential voltage across SRP and SRN. ABS(SRP - SRN).		2	V
V_{DD}	VDD pin supply voltage range (LDO ouptut)	−0.3	2	V
V_{IOD}	Open-drain I/O pins (SDA, SCL)	−0.3	6	V
V_{PROG}	PROG pin	−0.3	7.8	V
V_{IOPP}	Push-Pull I/O pins (TEST)	−0.3	$[V_{DD} + 0.3]$	V
T_A	Operating free-air temperature range	−40	85	°C
T_{STG}	Storage temperature range	−65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

T_A = 30°C and V_{REGIN} = V_{BAT} = 3.6V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{BAT}[1]	External input capacitor for internal LDO between BAT and V_{SS}	Nominal capacitor values specified. Recommend a 5% ceramic X5R type capacitor located close to the device.		0.1		µF
C_{LDO18} [1]	External output capacitor for internal LDO between V_{DD} and V_{SS}			0.47		µF
V_{PU} [1]	External pull-up voltage for open-drain pins (SDA, SCL, PROG)		1.62		3.6	V
V_{PV}	PROG Programming Voltage [RA0]	T_A = 15°C to 35°C. OTP Programming mode only.	7.3	7.4	7.5	V
I_{PV}	PROG Programming Current [RA0]			4	5	mA

(1) Specified by design. Not production tested.

SUPPLY CURRENT

T_A = 30°C and V_{REGIN} = V_{BAT} = 3.6V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I_{CC} [1]	NORMAL mode current	I_{LOAD} > *Sleep Current* [2]		93		µA
I_{SLP} [1]	SLEEP mode current	I_{LOAD} < *Sleep Current* [2]		21		µA
I_{HIB} [1]	HIBERNATE mode current	I_{LOAD} < *Hibernate Current* [2]		9		µA
I_{SD} [1]	SHUTDOWN mode current	Fuel gauge in host commanded SHUTDOWN mode. (LDO Regulator Output Disabled.)		0.6		µA

(1) Specified by design. Not production tested.
(2) Wake Comparator Disabled.

DIGITAL INPUT AND OUTPUT DC CHARACTERISTICS

T_A = –40°C to 85°C, typical values at T_A = 30°C and V_{REGIN} = 3.6 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH(OD)}$	Input voltage, high [2]	External pullup resistor to V_{PU}	V_{PU} x 0.7			V
$V_{IH(PP)}$	Input voltage, high [3]		1.4			V
V_{IL}	Input voltage, low [2] [3]				0.6	V
V_{OL}	Output voltage, low [2]				0.6	V
I_{OH}	Output source current, high [2]				0.5	mA
$I_{OL(OD)}$	Output sink current, low [2]				-3	mA
C_{IN} [1]	Input capacitance [2] [3]				5	pF
I_{lkg}	Input leakage current [2] [3]	SCL, SDA, and TEST pins			0.1	µA
		PROG pin			1.0	

(1) Specified by design. Not production tested.
(2) Open Drain pins: (SCL, SDA, PROG)
(3) Push Pull pin: (TEST)

LDO REGULATOR, WAKE-UP AND AUTO-SHUTDOWN DC CHARACTERISTICS

T_A = –40°C to 85°C, typical values at T_A = 30°C and V_{REGIN} = 3.6 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{BAT}	BAT pin regulator input		2.45		4.5	V
V_{DD}	Regulator output voltage			1.8		V
$UVLO_{IT+}$	V_{BAT} Under Voltage Lock Out LDO Wake-Up Rising Threshold			2		V
$UVLO_{IT-}$	V_{BAT} Under Voltage Lock Out LDO Auto-Shutdown Falling Threshold			1.95		V

(1) Specified by design. Not production tested.

ADC (TEMPERATURE AND CELL MEASUREMENT) CHARACTERISTICS

T_A = –40°C to 85°C; typical values at T_A = 30°C and V_{REGIN} = 3.6 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IN(BAT)}$	BAT pin voltage measurement range.	Voltage divider enabled.	2.45		4.5	V
t_{ADC_CONV}	Conversion time			125		ms
	Effective Resolution			15		bits

(1) Specified by design. Not tested in production.

INTEGRATING ADC (COULOMB COUNTER) CHARACTERISTICS

T_A = –40°C to 85°C; typical values at T_A = 30°C and V_{REGIN} = 3.6 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{SR}	Input voltage range from BAT to SRX pins			BAT ± 25		mV
t_{SR_CONV}	Conversion time	Single conversion		1		s
	Effective Resolution	Single conversion		16		bits

(1) Specified by design. Not tested in production.

I²C-COMPATIBLE INTERFACE COMMUNICATION TIMING CHARACTERISTICS

T_A = –40°C to 85°C; typical values at T_A = 30°C and V_{REGIN} = 3.6 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Standard Mode (100 kHz)						
$t_{d(STA)}$	Start to first falling edge of SCL		4			µs
$t_{w(L)}$	SCL pulse duration (low)		4.7			µs
$t_{w(H)}$	SCL pulse duration (high)		4			µs
$t_{su(STA)}$	Setup for repeated start		4.7			µs
$t_{su(DAT)}$	Data setup time	Host drives SDA	250			ns
$t_{h(DAT)}$	Data hold time	Host drives SDA	0			ns
$t_{su(STOP)}$	Setup time for stop		4			µs
$t_{(BUF)}$	Bus free time between stop and start	Includes Command Waiting Time	66			µs
t_f	SCL/SDA fall time [1]				300	ns
t_r	SCL/SDA rise time [1]				300	ns
f_{SCL}	Clock frequency [2]				100	kHz
Fast Mode (400 kHz)						
$t_{d(STA)}$	Start to first falling edge of SCL		600			ns
$t_{w(L)}$	SCL pulse duration (low)		1300			ns
$t_{w(H)}$	SCL pulse duration (high)		600			ns
$t_{su(STA)}$	Setup for repeated start		600			ns
$t_{su(DAT)}$	Data setup time	Host drives SDA	100			ns
$t_{h(DAT)}$	Data hold time	Host drives SDA	0			ns
$t_{su(STOP)}$	Setup time for stop		600			ns
$t_{(BUF)}$	Bus free time between stop and start	Includes Command Waiting Time	66			µs
t_f	SCL/SDA fall time [1]				300	ns
t_r	SCL/SDA rise time [1]				300	ns
f_{SCL}	Clock frequency [2]				400	kHz

(1) Specified by design. Not production tested.
(2) If the clock frequency (f_{SCL}) is > 100 kHz, use 1-byte write commands for proper operation. All other transactions types are supported at 400 kHz. (Refer to I²C INTERFACE and I²C Command Waiting Time)
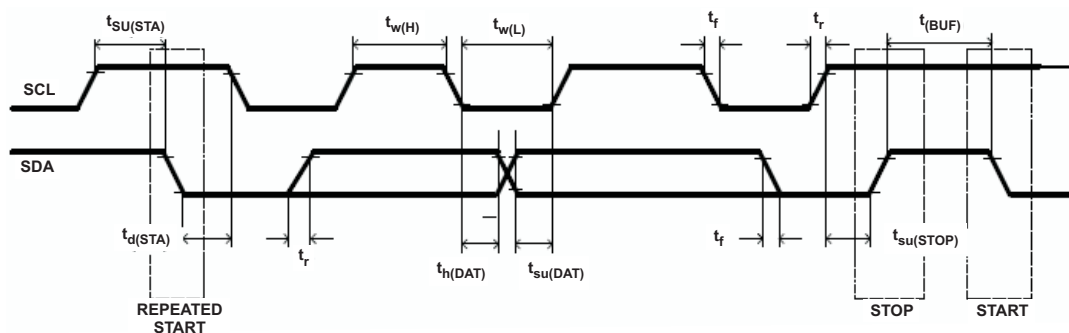
Figure 1. I²C-Compatible Interface Timing Diagrams

GENERAL DESCRIPTION

The bq27411-G1 accurately predicts the battery capacity and other operational characteristics of a single Li-based rechargeable cell. It can be interrogated by a system processor to provide cell information, such as state-of-charge (SOC). The bq27411-G1 is available in several options optimized for different battery cell chemistries. (See AVAILABLE OPTIONS table.) Configuration parameters unique to the customer's application are programmed in OTP memory at the customer's factory using a 7.4V typical voltage applied to the PROG pin and a set of I^2C programming commands. More details are available in the *SmartFlash OTP Programming (SLUA703)* document.

Information is accessed through a series of commands, called *Standard Commands.* Further capabilities are provided by the additional *Extended Commands* set. Both sets of commands, indicated by the general format *Command( )*, are used to read and write information contained within the bq27411-G1 control and status registers, as well as its data locations.

The key to the bq27411-G1's high-accuracy gas gauging prediction is Texas Instrument's proprietary Impedance Track™ algorithm. This algorithm uses cell measurements, characteristics, and properties to create state-of-charge predictions that can achieve high accuracy across a wide variety of operating conditions and over the lifetime of the battery.

The bq27411-G1 measures charge/discharge activity by monitoring the voltage across a small-value sense resistor. When a cell is attached to the bq27411-G1, cell impedance is computed, based on cell current, cell open-circuit voltage (OCV), and cell voltage under loading conditions.

The bq27411-G1 uses an integrated temperature sensor for estimating cell temperature. Alternatively, the host processor can provide temperature data for the bq27411-G1.

To minimize power consumption, the bq27411-G1 has several power modes: INITIALIZATION, NORMAL, SLEEP, and HIBERNATE. The bq27411-G1 passes automatically between these modes, depending upon the occurrence of specific events, though a system processor can initiate some of these modes directly. More details are found in the *bq27411-G1 Technical Reference Manual (SLUUAS7)*.

NOTE

Formatting Conventions in this Document:

Commands: *italics* with parentheses( ) and no breaking spaces, for example, *RemainingCapacity( )*.

Data Flash: *italics*, **bold**, and breaking spaces, for example, **Design Capacity**.

Register bits and flags: *italics* with brackets [ ], for example, *[TDA]*

Data flash bits: *italics*, **bold**, and brackets [ ], for example, **[LED1]**

Modes and states: ALL CAPITALS, for example, UNSEALED mode.

DATA COMMANDS

STANDARD DATA COMMANDS

The bq27411-G1 uses a series of 2-byte standard commands to enable system reading and writing of battery information. Each standard command has an associated command-code pair, as indicated in . Because each command consists of two bytes of data, two consecutive I^2C transmissions must be executed both to initiate the command function, and to read or write the corresponding two bytes of data. Additional details are found in the bq27411-G1 Technical Reference Manual (SLUUAS7).

Table 1. Standard Commands

NAME		COMMAND CODE	UNITS	SEALED ACCESS
Control( )	CNTL	0x00 / 0x01	N/A	R/W
Temperature( )	TEMP	0x02 / 0x03	0.1°K	R/W
Voltage( )	VOLT	0x04 / 0x05	mV	R
Flags( )	FLAGS	0x06 / 0x07	N/A	R
NominalAvailableCapacity( )		0x08 / 0x09	mAh	R
FullAvailableCapacity( )		0x0a / 0x0b	mAh	R
RemainingCapacity( )	RM	0x0c / 0x0d	mAh	R
FullChargeCapacity( )	FCC	0x0e / 0x0f	mAh	R
AverageCurrent( )		0x10 / 0x11	mA	R
StandbyCurrent( )		0x12 / 0x13	mA	R
MaxLoadCurrent( )		0x14 / 0x15	mA	R
AveragePower( )		0x18 / 0x19	mW	R
StateOfCharge( )	SOC	0x1c / 0x1d	%	R
IntTemperature( )		0x1e / 0x1f	0.1°K	R
StateOfHealth( )	SOH	0x20 / 0x21	num / %	R

Control( ): 0x00/0x01

Issuing a *Control( )* command requires a subsequent 2-byte subcommand. These additional bytes specify the particular control function desired. The *Control( )* command allows the system to control specific features of the bq27411-G1 during normal operation and additional features when the device is in different access modes, as described in . Additional details are found in the bq27411-G1 Technical Reference Manual (SLUUAS7).

Table 2. *Control( )* Subcommands

CNTL FUNCTION	CNTL DATA	SEALED ACCESS	DESCRIPTION
CONTROL_STATUS	0x0000	Yes	Reports the status of device.
DEVICE_TYPE	0x0001	Yes	Reports the device type (0x0421).
FW_VERSION	0x0002	Yes	Reports the firmware version of the device.
DM_CODE	0x0004	Yes	Reports the Data Memory Code number stored in NVM.
PREV_MACWRITE	0x0007	Yes	Returns previous MAC command code.
CHEM_ID	0x0008	Yes	Reports the chemical identifier of the Impedance Track™ configuration
SET_HIBERNATE	0x0011	Yes	Forces CONTROL_STATUS [*HIBERNATE*] to 1.
CLEAR_HIBERNATE	0x0012	Yes	Forces CONTROL_STATUS [*HIBERNATE*] to 0.
SET_CFGUPDATE	0x0013	No	Force CONTROL_STATUS [*CFGUPMODE*] to 1 and gauge enters CONFIG UPDATE mode.
SEALED	0x0020	No	Places the device in SEALED access mode.
RESET	0x0041	No	Performs a full device reset.
SOFT_RESET	0x0042	No	Gauge exits CONFIG UPDATE mode.

FUNCTIONAL DESCRIPTION

I^{2}C INTERFACE

The bq27411-G1 supports the standard I^{2}C read, incremental read, quick read, one-byte write, and incremental write functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101. The first 8 bits of the I^{2}C protocol are, therefore, 0xAA or 0xAB for write or read, respectively.

(a) 1-byte write

(b) quick read
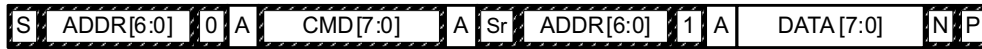
(c) 1- byte read
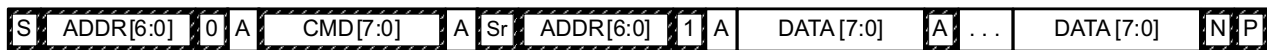
(d) incremental read

(e) incremental write

(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop).

The quick read returns data at the address indicated by the address pointer. The address pointer, a register internal to the I^{2}C communication engine, increments whenever data is acknowledged by the bq27411-G1 or the I^{2}C master. "Quick writes" function in the same manner and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

The following command sequences are not supported:

Attempt to write a read-only address (NACK after data sent by master):
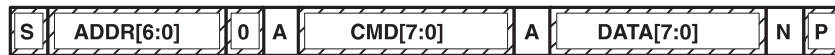
Attempt to read an address above 0x6B (NACK command):

I^{2}C Time Out

The I^{2}C engine releases both SDA and SCL if the I^{2}C bus is held low for 2 seconds. If the bq27411-G1 is holding the lines, releasing them frees them for the master to drive the lines. If an external condition is holding either of the lines low, the I^{2}C engine enters the low-power sleep mode.

I²C Command Waiting Time

To ensure proper operation at 400 kHz, a $t_{(BUF)} \geq 66$ µs bus-free waiting time must be inserted between all packets addressed to the bq27411-G1. In addition, if the SCL clock frequency (f_{SCL}) is > 100 kHz, use individual 1-byte write commands for proper data flow control. The following diagram shows the standard waiting time required between issuing the control subcommand the reading the status result. For read-write standard command, a minimum of 2 seconds is required to get the result updated. For read-only standard commands, there is no waiting time required, but the host must not issue any standard command more than two times per second. Otherwise, the gauge could result in a reset issue due to the expiration of the watchdog timer.
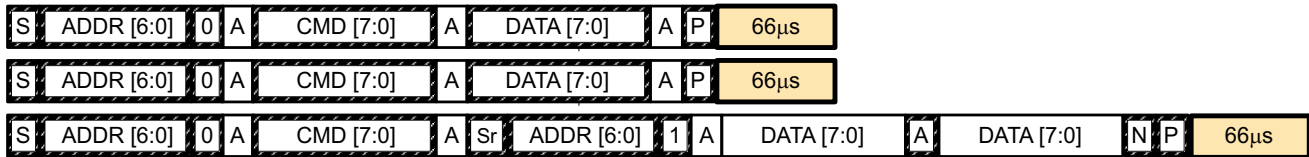
Waiting time inserted between two 1-byte write packets for a subcommand and reading results
(required for 100 kHz < $f_{SCL} \leq$ 400 kHz)
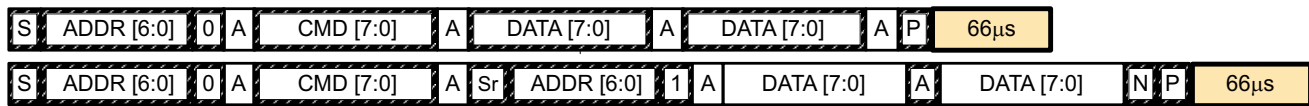
Waiting time inserted between incremental 2-byte write packet for a subcommand and reading results
(acceptable for $f_{SCL} \leq$ 100 kHz)

Waiting time inserted after incremental read

I²C Clock Stretching

A clock stretch can occur during all modes of fuel gauge operation. In SLEEP and HIBERNATE modes, a short ≤ 100 µs clock stretch occurs on all I²C traffic as the device must wake-up to process the packet. In the other modes (INITIALIZATION , NORMAL) a ≤ 4 ms clock stretching period may occur within packets addressed for the fuel gauge as the I²C interface performs normal data flow control.

REFERENCE SCHEMATIC
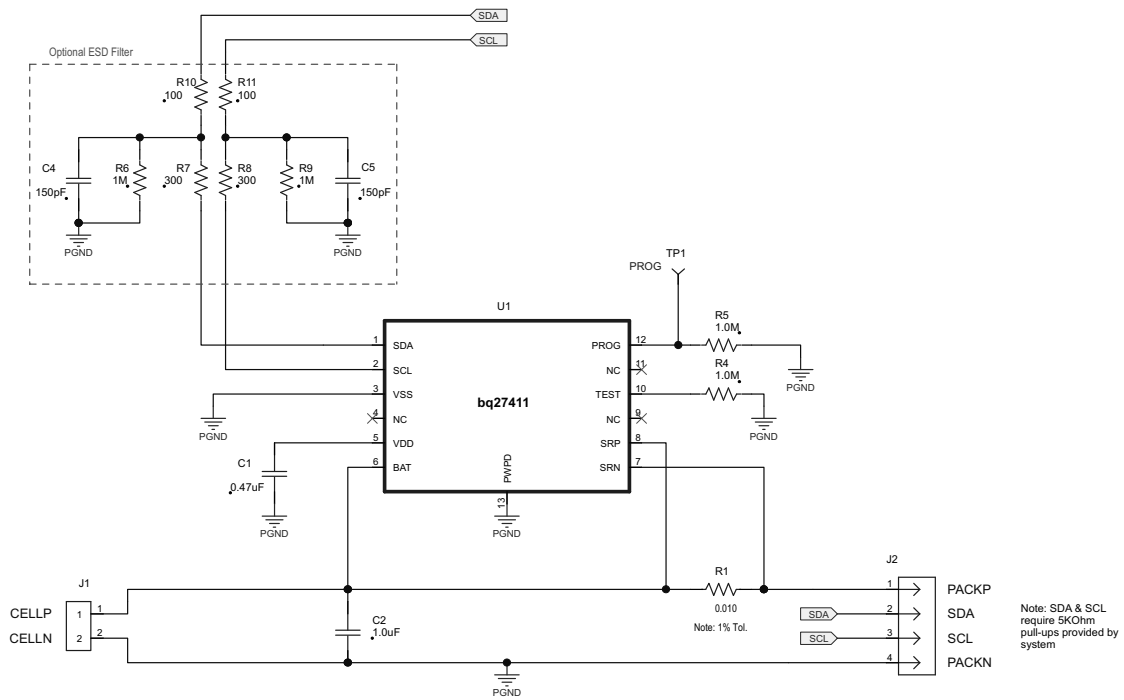
PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
BQ27411DRZ-G1A	PREVIEW	SON	DRZ	12		TBD	Call TI	Call TI	-40 to 85		
BQ27411DRZ-G1C	PREVIEW	SON	DRZ	12		TBD	Call TI	Call TI	-40 to 85		
BQ27411DRZR-G1A	ACTIVE	SON	DRZ	12	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 411A	Samples
BQ27411DRZR-G1C	ACTIVE	SON	DRZ	12	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 411C	Samples
BQ27411DRZT-G1A	ACTIVE	SON	DRZ	12	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 411A	Samples
BQ27411DRZT-G1C	ACTIVE	SON	DRZ	12	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 411C	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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TAPE AND REEL INFORMATION

REEL DIMENSIONS

TAPE DIMENSIONS

A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ27411DRZR-G1A	SON	DRZ	12	3000	330.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27411DRZR-G1C	SON	DRZ	12	3000	330.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27411DRZT-G1A	SON	DRZ	12	250	180.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27411DRZT-G1C	SON	DRZ	12	250	180.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2

TEXAS INSTRUMENTS

PACKAGE MATERIALS INFORMATION

TAPE AND REEL BOX DIMENSIONS

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ27411DRZR-G1A	SON	DRZ	12	3000	367.0	367.0	35.0
BQ27411DRZR-G1C	SON	DRZ	12	3000	367.0	367.0	35.0
BQ27411DRZT-G1A	SON	DRZ	12	250	210.0	185.0	35.0
BQ27411DRZT-G1C	SON	DRZ	12	250	210.0	185.0	35.0

PIN 1 INDEX AREA

0,20 REF.

SEATING PLANE

6X 0,50 / 0,30

0,40

1   6

12   7   6X 0,25 / 0,15

⊕ | ⌀ 0,10 Ⓜ | C | A | B

EXPOSED THERMAL PAD

4207806/B 04/06

2,60 / 2,40

4,15 / 3,85

1,00 / 0,80

⌒ 0,08

0,05 / 0,00

NOTES: A.   All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
          B.   This drawing is subject to change without notice.
          C.   Small Outline No–Lead (SON) package configuration.
          D.   The package thermal pad must be soldered to the board for thermal and mechanical performance.
               See the Product Data Sheet for details regarding the exposed thermal pad dimensions.
          E.   This package is lead–free.

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No−Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

Bottom View
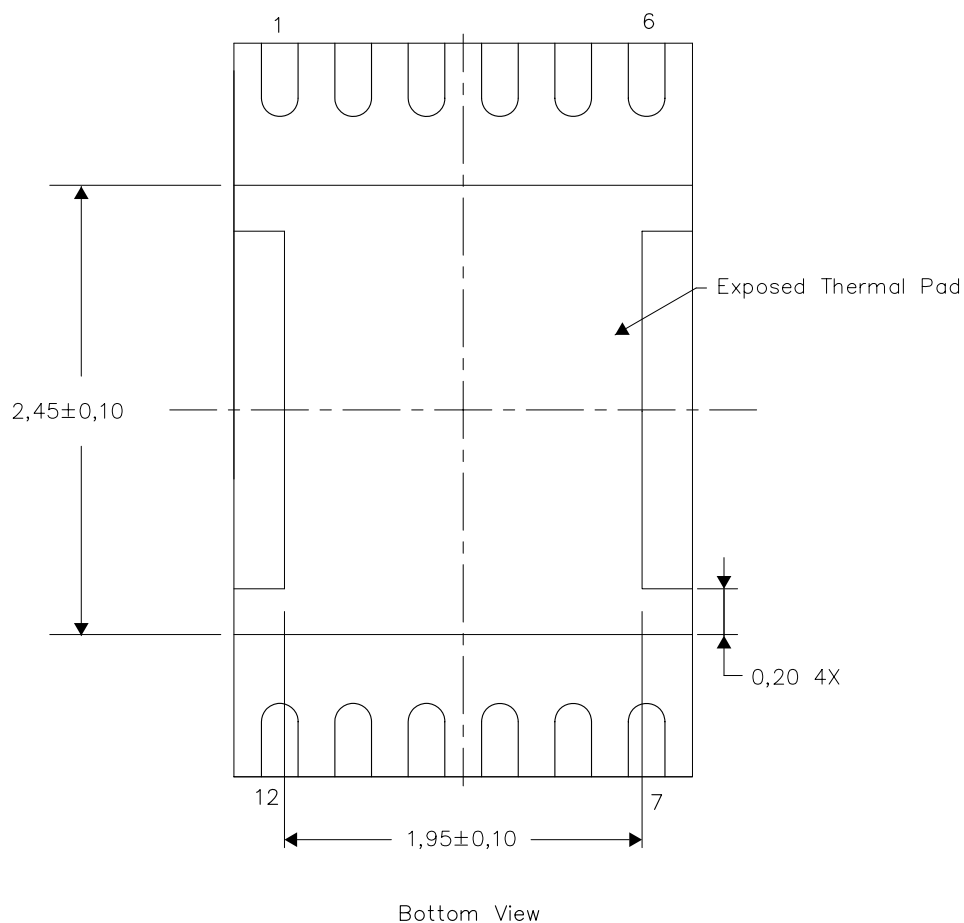
NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

4208114/E   06/10

DRZ (S−PDSO−N12)   PLASTIC SMALL OUTLINE NO−LEAD
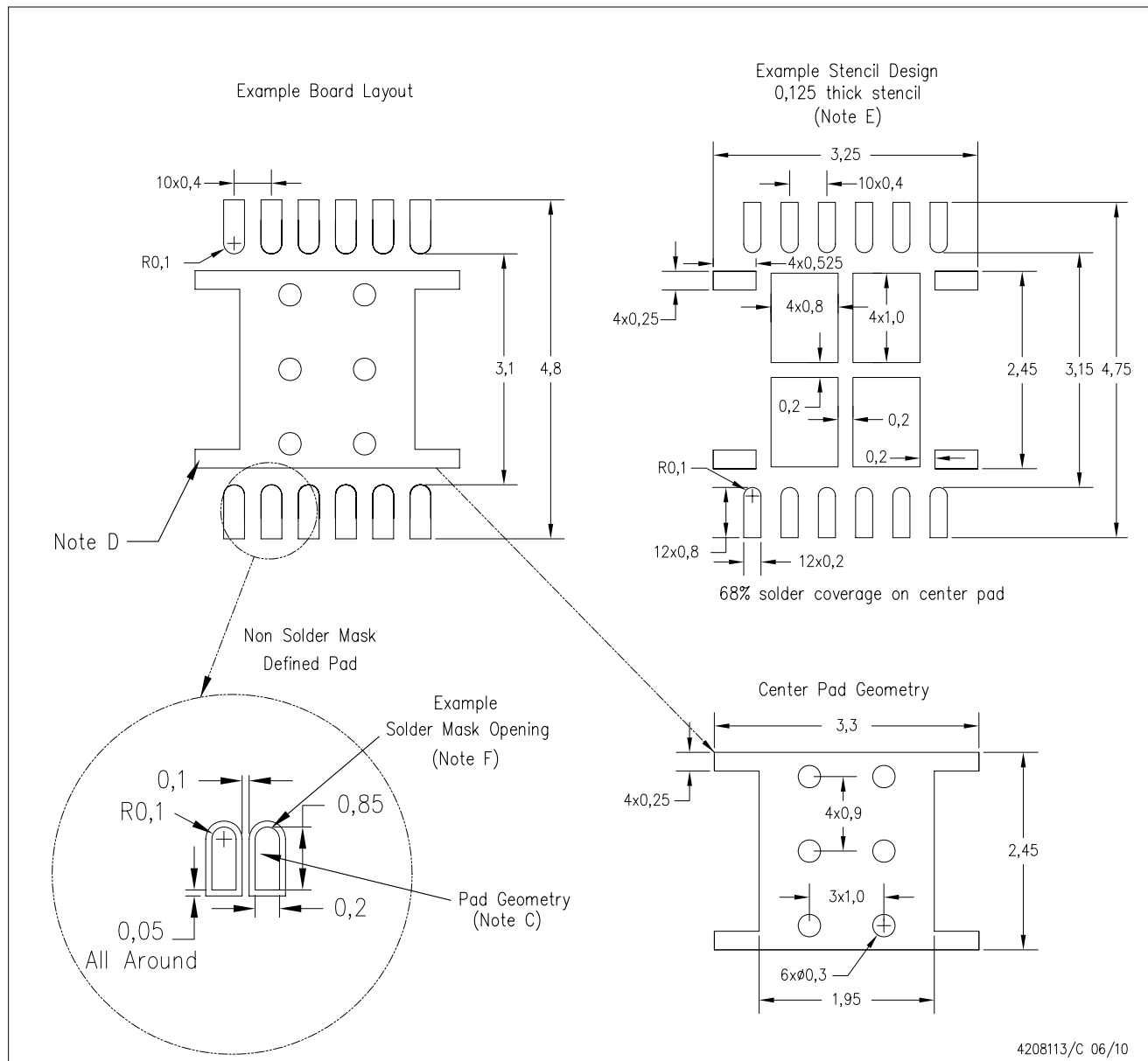
Example Board Layout

Example Stencil Design
0,125 thick stencil
(Note E)

10x0,4

R0,1

3,25

10x0,4

4x0,525

4x0,8   4x1,0

4x0,25

3,1   4,8

2,45   3,15 4,75

0,2   0,2

Note D

0,2

R0,1

12x0,8   12x0,2

68% solder coverage on center pad

Non Solder Mask
Defined Pad

Example
Solder Mask Opening
(Note F)

Center Pad Geometry

0,1

R0,1

0,85

3,3

4x0,25

4x0,9

0,2

Pad Geometry
(Note C)

2,45

0,05

All Around

3x1,0

6xØ0,3

1,95

4208113/C 06/10

NOTES: A. All linear dimensions are in millimeters.
        B. This drawing is subject to change without notice.
        C. Publication IPC−7351 is recommended for alternate designs.
        D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat−Pack
            Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets
            for specific thermal information, via requirements, and recommended board layout. These documents are available at
            www.ti.com <http://www.ti.com>.
        E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should
            contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
        F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.